



FQD10N20C / FQU10N20C

200V N-Channel MOSFET

General Description

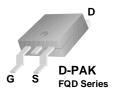
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, DC-AC converters for uninterrupted power supplies and motor controls.

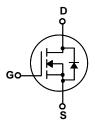
Features

- 7.8A, 200V, $R_{DS(on)} = 0.36\Omega @V_{GS} = 10 V$
- Low gate charge (typical 20 nC)
- Low Crss (typical 40.5 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS Compliant









Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQD10N20C / FQU10N20C	Units
V_{DSS}	Drain-Source Voltage		200	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		7.8	Α
			5.0	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	31.2	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	210	mJ
I _{AR}	Avalanche Current	(Note 1)	7.8	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	5.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P_D	Power Dissipation (T _C = 25°C)		50	W
	- Derate above 25°C		0.4	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*		50	°C/W
R _{θJA} Thermal Resistance, Junction-to-Ambient			110	°C/W
*When mounted on the minimum pad size recommended (PCB Mount)				

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	200			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.28		V/°C
I _{DSS}	7 0 1 1/1 5 1 0 1	V _{DS} = 200 V, V _{GS} = 0 V			10	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 160 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward V _{GS} = 30 V, V _{DS} = 0 V				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	Current, Reverse $V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 3.9 A		0.29	0.36	Ω
g _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 3.9 A (Note 4)		5.6		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		395 97	510 125	pF pF
C _{oss}	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz		97 40.5	125 53	pF pF
-155	reverse transfer supusitance			40.0	- 00	Pi
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 100 V, I _D = 9.5 A,		11	30	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		92	190	ns
$t_{d(off)}$	Turn-Off Delay Time			70	150	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		72	160	ns
Qg	Total Gate Charge	V _{DS} = 160 V, I _D = 9.5 A,		20	26	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		3.1		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		10.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				7.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current			-	31.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 7.8 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 9.5 A,		158		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.97		μС

Notes:1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 5.2mH, I_{AS} = 7.8A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} \leq 9.5A, di/dt \leq 300A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2% 5. Essentially independent of operating temperature

Typical Characteristics

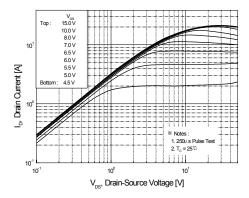


Figure 1. On-Region Characteristics

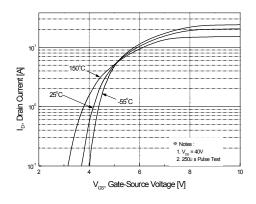


Figure 2. Transfer Characteristics

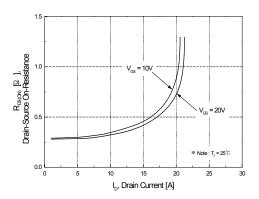


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

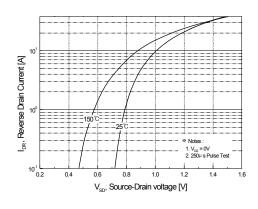


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

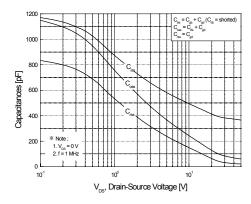


Figure 5. Capacitance Characteristics

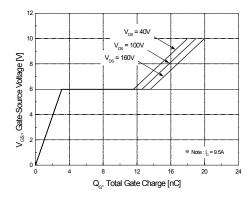
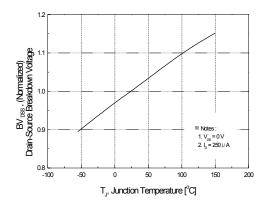


Figure 6. Gate Charge Characteristics

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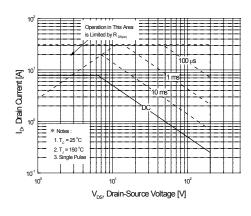
Typical Characteristics (Continued)



30 25 World 20 20 8 Notes: 1.1 V_{co} = 10V 2.1_c = 3.9 A 0.1_c = 10V 2.1_c = 10V 2.1_c

Figure 7. Breakdown Voltage Variation vs Temperature





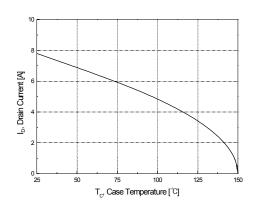


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

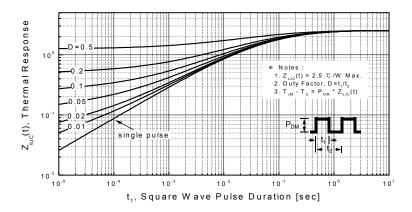
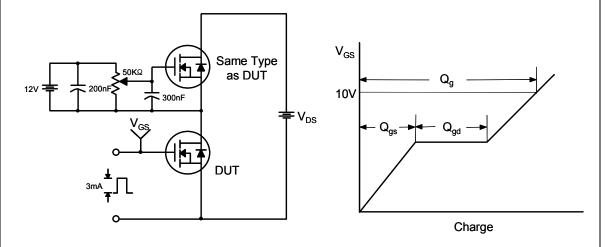


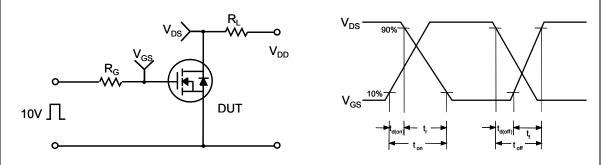
Figure 11. Transient Thermal Response Curve

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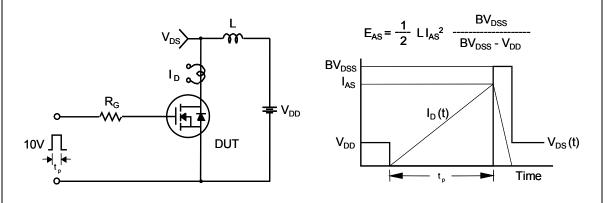
Gate Charge Test Circuit & Waveform



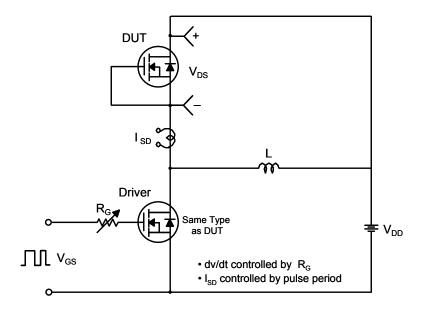
Resistive Switching Test Circuit & Waveforms

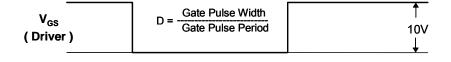


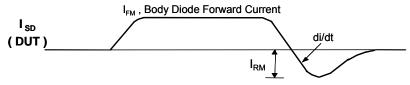
Unclamped Inductive Switching Test Circuit & Waveforms



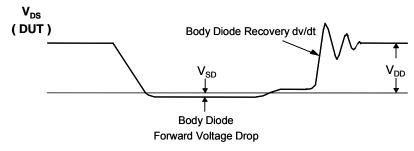
Peak Diode Recovery dv/dt Test Circuit & Waveforms







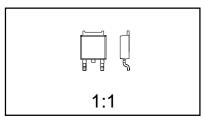
Body Diode Reverse Current



Package Dimensions

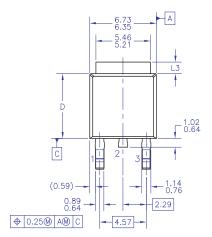
TO-252 (DPAK) (FS PKG Code 36)

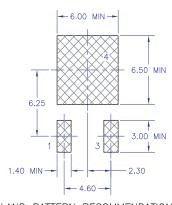




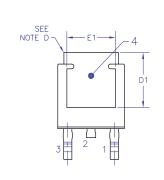
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

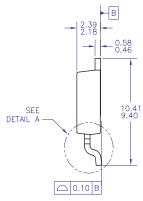
Part Weight per unit (gram): 0.33

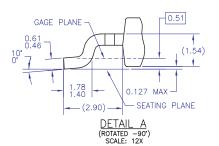




LAND PATTERN RECOMMENDATION







- NOTES: UNLESS OTHERWISE SPECIFIED

 A) ALL DIMENSIONS ARE IN MILLIMETERS.

 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

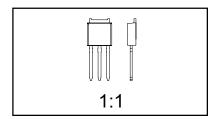
 - HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.
 DIMENSIONS L3,D,E1&D1 TABLE:

		OPTION AA	OPTION AB
	L3	0.89-1.27	1.52-2.03
_ [D	5.97-6.22	5.33-5.59
П	E1	4.32 MIN	3.81 MIN
Г	D1	5.21 MIN	4.57 MIN

Package Dimensions

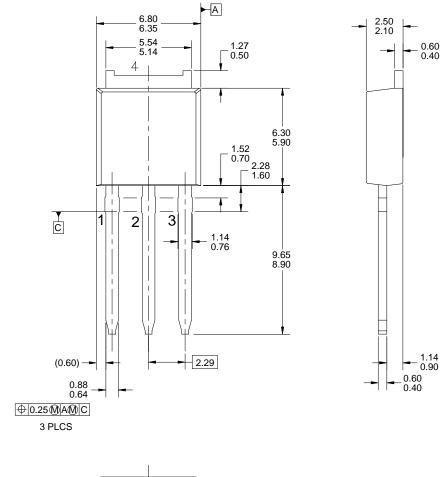
I - PAK

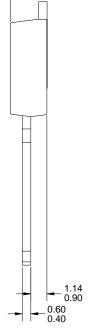




Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

Part Weight per unit (gram): 0.44





Dimensions in Millimeters

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